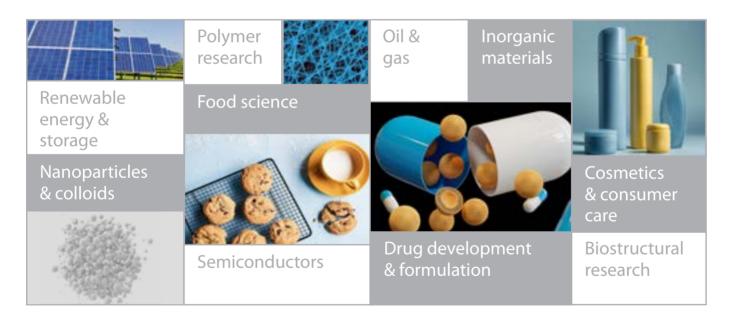


Discover Xenocs SAXS/WAXS solutions

Xenocs provides advanced X-ray solutions (SAXS/WAXS/USAXS and Imaging) for nanoscale materials characterization. Drawing on over 25 years of continuous innovation, we empower academic and industrial R&D labs worldwide with high-performance instruments, powerful software, and dedicated customer service. Headquartered in Grenoble, France, Xenocs operates globally through subsidiaries and local partners.

Multiple Applications



XSACT Pro Software



The Xenocs XSACT Pro software transforms scattering data analysis with its intuitive design and advanced analysis capabilities.

Featuring a wide range of algorithms, including unique modules for particle shape determination through model fitting or Al-powered classification, XSACT Pro streamlines data processing and interpretation for users of all experience levels.

Xeuss*

The Ultimate Solution for Nanoscale Characterization using SAXS/WAXS/GISAXS/USAXS/Imaging



Achieve precise nanoscale characterization for both scientific research and industrial applications.

- Ultimate Data Quality: With state-of-the-art optics and Clean Beam technology.
- Maximum Modular Versatility: Adapt to any experiment and obtain atomic- to mm-scale insights.
- Unlimited Experimental Possibilities: Large chamber with diverse environments and holders.
- Comprehensive Software Suite: Streamlined data acquisition, processing, and analysis.

Nano-inXider*

The Smart Solution for Nanoscale Characterization using SAXS/WAXS/GISAXS in a Compact System



Experience smart nanoscale characterization with exceptional ease of use and high performance, all in a compact, intelligent design.

- From Samples to Results: Automatic alignment, acquisition, and processing.
- High Dynamic Range Measurements:
 Beamstop-less acquisition and Clean Beam Technology.
- Atomic to Nanoscale Insights: Simultaneous SAXS and WAXS data collection..
- Low Cost of Ownership: Compact, energyefficient, and low-maintenance for daily use.